



\*Source: NREL, Degradation Mechanisms in TOPCon/POLO Solar Cells

Factory Witness, Characterizations and Light-induced Degradation Measurement										
Thermal Cycling	Damp Heat	Dark-Kinks Durability	Mechanical Stress	Wet Stress	Moisture-Induced	LETID Sensitivity	PERC/IBC IAM Profile	Field Exposure		
TC 200	DH 1000	DH 1000	Open Mechanical Load	TC 200	65 °C, 85%RH (50% and/or 192 hrs)	LETID 162 hrs (75°C, 100%RH)	IAM Profile	Exposure 6 Months		
Characterization	Characterization	UV 65 kWh/m <sup>2</sup>	Dynamic Mechanical Load	Characterization	Characterization	Characterization	IAM Profile	Characterization		
TC 200	DH 1000	Characterization	Dynamic Mechanical Load	Characterization	Characterization	LETID 162 hrs (75°C, 100%RH)		Field Exposure 6 Months		
Characterization	Characterization	TC 50 + HF 10	Characterization	Characterization	Characterization	Characterization		Field Exposure 6 Months		
TC 200	Stabilization 80°C, 1hr, 48 hrs	UV 65 kWh/m <sup>2</sup>	TC 50 + HF 10	Characterization	TC 50 + HF 10	LETID 162 hrs (75°C, 100%RH)		Characterization		
Characterization	Characterization	Characterization	Characterization	Characterization	Characterization	Characterization		Characterization		
		TC 50 + HF 10	Characterization	Characterization	Characterization	Characterization		Characterization		
		UV 65 kWh/m <sup>2</sup>	Characterization	Characterization	Characterization	Characterization		Characterization		